## Notice of References Cited

Application/Control No. 10/718,445	Applicant(s)/Patent Under Reexamination BHATIA, SANDEEP	
Examiner	Art Unit	
John J. Tahone Jr	2138	Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,418,545 B1	07-2002	Adusumilli, Swaroop	714/729
*	В	US-2003/0204802 A1	10-2003	Sim, Gyoochan	714/726
*	С	US-6,079,040 A	06-2000	Hom et al.	714/738
*	D	US-6,901,544 B1	05-2005	Huth et al.	714/731
*	Ε	US-2004/0078741 A1	04-2004	Morton, Gary	714/726
	F	US-			
	G	US-			
	Н	US-			
	i	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP2003-202362	07-2003	JP	MASATAKE. AOKI	G01R 31/28
	0					
	Р		,			
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Jaramillo et al., 10 Tips for Successful Scan Design: Part one, February 17, 2000, ednmag.com, pp. 67-73,75
	v	Jaramillo et al., 10 Tips for Successful Scan Design: Part two, February 17, 2000, ednmag.com, pp. 77,78,80,82,84,86,88,90.
	w	
	x	

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.